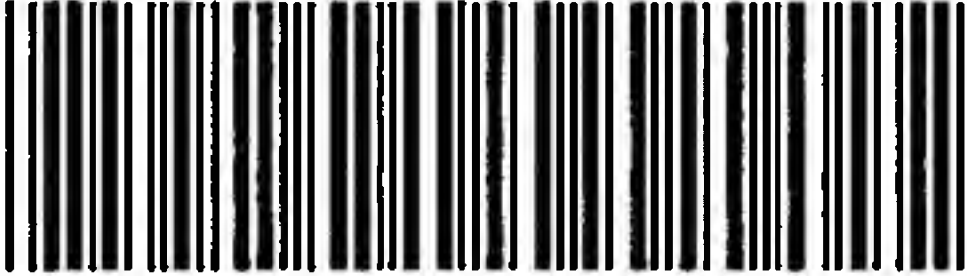


<div>Search Notes</div> <div></div>	Application No.	Applicant(s)	
	10/065,552	SAWADA ET AL.	
	Examiner	Art Unit	
	Wai-Sing Louie	2814	

SEARCHED			
Class	Subclass	Date	Examiner
438	14-18	11/15/2004	WSL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Wafer testing and measurement, carrier concentration, profiling, capacitance, voltage	11/15/2004	WSL